

Search Notes

Application/Control No.

10/071,456

Examiner

Anh D. Mai

Applicant(s)/Patent under
Reexamination

DICKERSON ET AL.

Art Unit

2814

SEARCHED

Class	Subclass	Date	Examiner
438	424	3/9/2005	A.M

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IEEE (web): * shallow trench isolation and CMOS * shallow trench isolated CMOS	3/9/2005	A.M